

Notice of References Cited	Application/Control No. 10/770,074		Applicant(s)/Patent Under Reexamination HAY, JENNIFER	
	Examiner Toan M. Le		Art Unit 2863	Page 1 of 1

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*	B	US-6,778,916	08-2004	Lee, Hyung Yil	702/42
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NON-PATENT DOCUMENTS

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	W	Syed Asif et al., Quantitative Imaging of Nanoscale Mechanical Properties Using Hybrid Nanoindentation and Force Modulation, 1 August 2001, Journal of Applied Physics, Vol. 90, No. 3, Pages 1192-1200
	X	Schwarzer et al., Contact Modeling in the Vicinity of an Edge, 2001, Surface and Coatings Technology 146-147, Pages 371-377

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.